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**SUPPLEMENTAL INFORMATION  
DISCLOSURE STATEMENT BY  
APPLICANT**

(use as many sheets as necessary)

Complete if Known	
Application Number	10/754,002
Filing Date	01/08/2004
First Named Inventor	Daniel E. Resasco et al.
Group Art Unit	1754 (Conf. No. 6016)
Examiner Name	S. Hendrickson
Attorney Docket Number	5820.645

U. S. PATENT DOCUMENTS						
EXAM INIT.	Cite No. 1	U.S. PATENT NUMBER Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD- YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
SLP		5424054		Bethune	06/13/1995	
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### U. S. PATENT DOCUMENTS

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SLA		6699457		Cortright et al.	03/02/2004	
SLA		6761870		Smalley et al.	07/13/2004	
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EXAM INIT.	Cite No. 1	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM- DD-YYYY	Pages, Columns, Lines Lines, Where Relevant Passages or Relevant Figures Appear	T*
		Office 3	Number 4	Kind Codes (if known)			
SLD			PCT/US03/19664		International Search Report	03/31/2004	
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EXAM INIT.		<b>NON PATENT DOCUMENTS</b>
		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published
SLA		CHATTOPADHYAY, et al., "A Route for Bulk Separation of Semiconducting from Metallic Singel-Wall Carbon Nanotubes", Journal of American Chemical Society, Vol. 125, No. 11, pp. 3370-3375, 2003.
SLA		CHEN et al., "Bulk Separative Enrichment in Metallic or Semiconducting Single-Walled Carbon Nanotubes", Nano Letters, xxxx Vol. 0, No. 0, page est: 4.9 A-E.
SLA		Patent Abstracts of Japan, Vol. 1996, no. 12, December 26, 1996, and JP 0 8 198611 A (NEC CORP), Aug. 6, 1996, Abstract.
SLA		<sup>TOHJI</sup> <del>TAHJI</del> et al., "Purification Procedure for Single-Wall Nanotubes", J. Phys. Chem. B, Vol. 101, pp. 1974-1978 (1997).
<b>Non Patent Documents:</b> <sup>1</sup> Unique citation designation number. <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.		
Examiner Signature: <u>Hendrickson</u>		Date Considered: <u>12/10/04</u>
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